JJMICROELECTRONICS

60V, 5A, $32m\Omega$ N-channel Power Trench MOSFET

JMTP330N06D

Features

- Excellent $R_{\text{DS}(\text{ON})}$ and Low Gate Charge
- 100% UIS TESTED
- Halogen-free; RoHS-compliant
- Pb-free plating

Applications

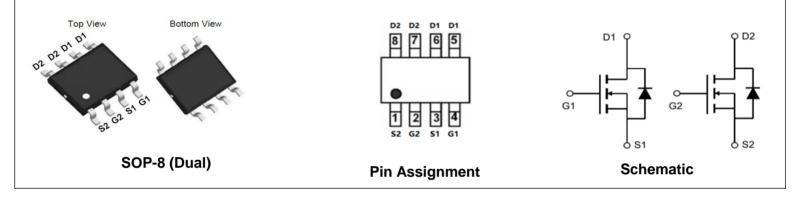
- Load Switch
- PWM Application
- Power Management

Product Summary

Parameters	Value	Unit
V _{DSS}	60	V
V _{GS(th)_Typ}	1.6	V
I _D (@V _{GS} =10V)	5	А
R _{DS(ON)_Typ} (@V _{GS} =10V	28	mΩ
$R_{DS(ON)_Typ}$ (@V _{GS} =4.5V	32	mΩ







Ordering Information

Device	Marking	MSL	Form	Package	Reel(pcs)	Per Carton (pcs)
JMTP330N06D	33N06D	3	Tape&Reel	SOP-8	4000	48000

Absolute Maximum Ratings (@ $T_A = 25^{\circ}C$ unless otherwise specified)

Symbol	Parameter		Value	Unit	
V _{DS}	Drain-to-Source Voltage		60	V	
V_{GS}	Gate-to-Source Voltage		±20	V	
1_		$T_A = 25^{\circ}C$	5	А	
٦D		$T_A = 100^{\circ}C$	4	A	
I _{DM}	Pulsed Drain Current ⁽¹⁾		Refer to Fig.4	A	
E _{AS}	Single Pulsed Avalanche Energy ⁽²⁾		31	mJ	
P _D	Power Dissipation	$T_A = 25^{\circ}C$	1.4	W	
۰D		$T_{A} = 100^{\circ}C$	0.6	vv	
T _J , T _{STG}	Junction & Storage Temperature Range		-55 to 150	°C	

Thermal Characteristics

Symbol	Parameter	Мах	Unit
R _{θJA}	Thermal Resistance, Junction to Ambient ⁽³⁾	124	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient ⁽⁴⁾	91	C/VV

					-	-
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Off Cha	aracteristics					
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	60	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 60V, V_{GS} = 0V$	-	-	1.0	μA
I _{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA
On Cha	racteristics			•		
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1.0	1.6	2.5	V
D		$V_{GS} = 10V, I_D = 5A$	-	28	38	mΩ
R _{DS(ON)}	Static Drain-Source ON-Resistance ⁽⁵⁾	$V_{GS} = 4.5V, I_{D} = 3A$	-	32	47	mΩ
Dynami	ic Characteristics					
R_g	Gate Resistance	f = 1MHz	-	2	-	Ω
C _{iss}	Input Capacitance		-	743	-	pF
C _{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 30V,$ f = 1MHz	-	126	-	pF
C _{rss}	Reverse Transfer Capacitance		-	50	-	pF
Qg	Total Gate Charge		-	24	-	nC
Q _{gs}	Gate Source Charge	$V_{GS} = 0 \text{ to } 4.5V$ $V_{DS} = 30V, I_D = 5A$	-	4	-	nC
Q_{gd}	Gate Drain("Miller") Charge		-	4	-	nC
	•					
Switchi	ing Characteristics		F	T	I	
t _{d(on)}	Turn-On DelayTime		-	8	-	ns
t _r	Turn-On Rise Time	$V_{GS} = 10V, V_{DD} = 30V$	-	29	-	ns
t _{d(off)}	Turn-Off DelayTime	$I_D = 5A, R_{GEN} = 3\Omega$	-	32	-	ns
t _f	Turn-Off Fall Time		-	2	-	ns
Body D	iode Characteristics				-	
I _S	Maximum Continuous Body Diode Forward Current		-	-	5	А
I _{SM}	Maximum Pulsed Body Diode Forward Current		-	-	20	А
$V_{\rm SD}$	Body Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 5A$	-		1.2	V
trr	Body Diode Reverse Recovery Time	1 - 50 di/dt - 1000/mc	-	24	-	ns
Qrr	Body Diode Reverse Recovery Charge	I _F = 5A, di/dt = 100A/us	-	22	-	nC

Electrical Characteristics ($T_J = 25^{\circ}C$ unless otherwise specified)

Notes: 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

 $2. \ E_{AS} \ condition: \ Starting \ T_J=25C, \ V_{DD}=30V, \ V_G=10V, \ R_G=25ohm, \ L=0.5mH, \ I_{AS}=9.1A, \ V_{DD}=0V \ during \ time \ in \ avalanche.$

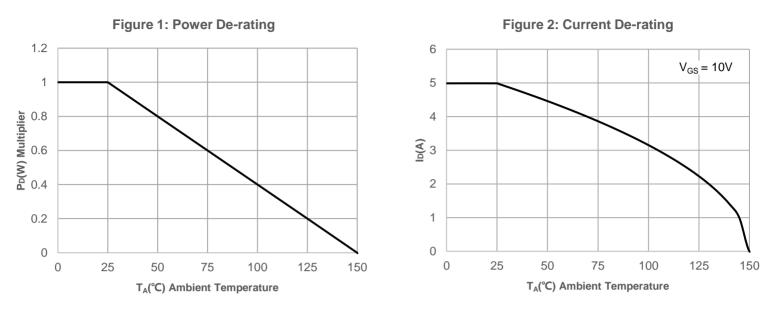
3. $R_{\theta JA}$ is measured with the device mounted on a minimum recommended pad of 2oz copper FR4 PCB.

4. $R_{\theta JA}$ is measured with the device mounted on a 1inch² pad of 2oz copper FR4 PCB.

5. Pulse Test: Pulse Width ${\leqslant}300\mu s,$ Duty Cycle ${\leqslant}0.5\%.$







Typical Performance Characteristics



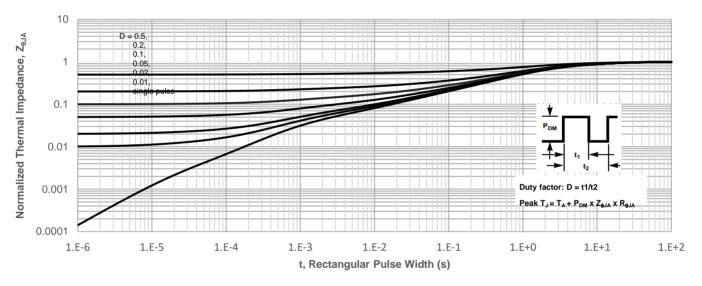
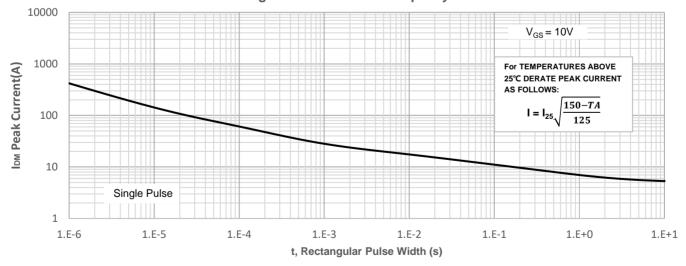


Figure 4: Peak Current Capacity



Typical Performance Characteristics

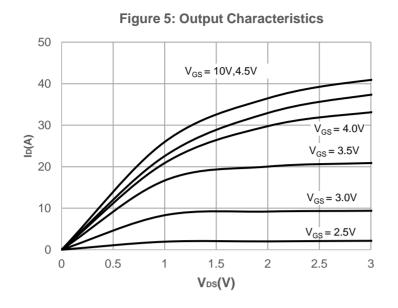
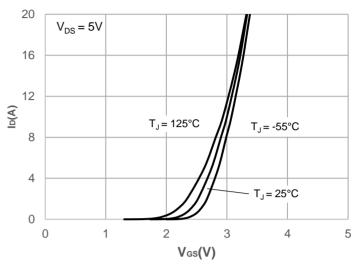


Figure 6: Typical Transfer Characteristics



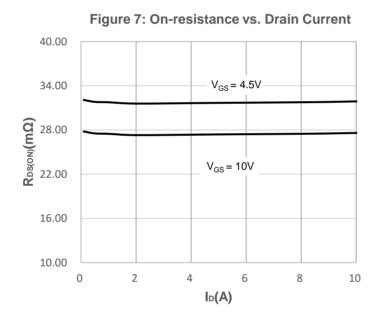


Figure 9: Gate Charge Characteristics

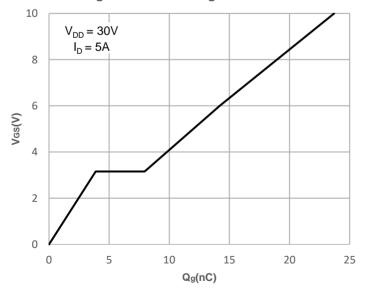
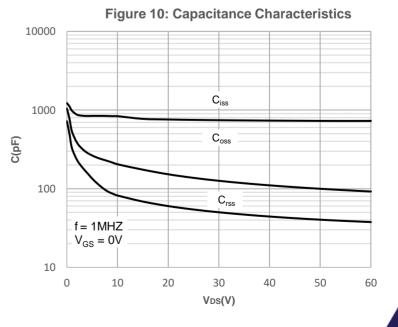
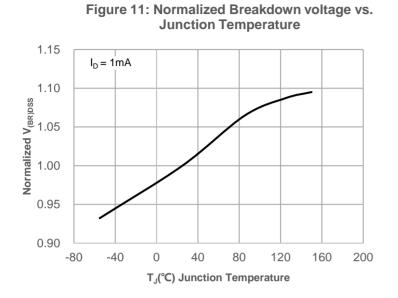


Figure 8: Body Diode Characteristics 100 $V_{GS} = 0V$ 10 Is(A) 1 T_J = 125°C T_J=-55°C 0.1 T_J= 25°C 0.01 0 0.2 0.4 0.6 0.8 1 1.2 Vsd(V)

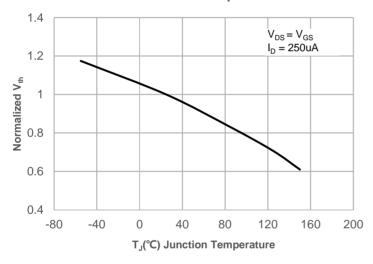


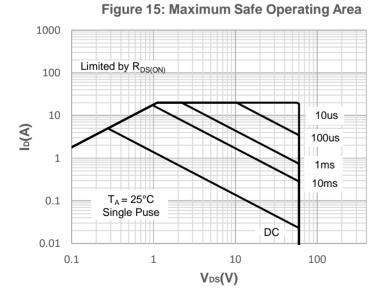


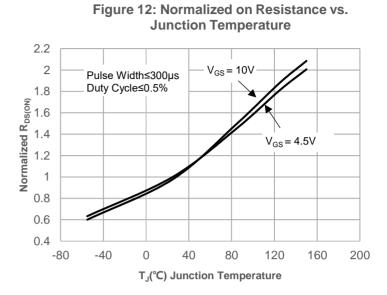
Typical Performance Characteristics



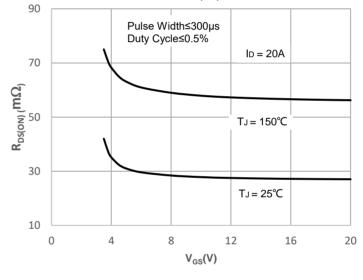














Test Circuit

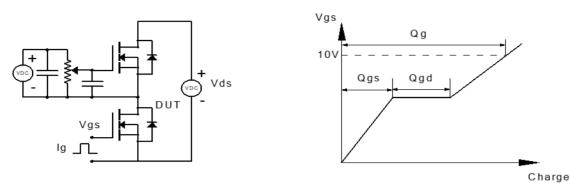


Figure 1: Gate Charge Test Circuit & Waveform

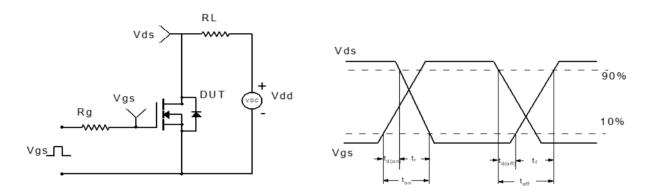


Figure 2: Resistive Switching Test Circuit & Waveform

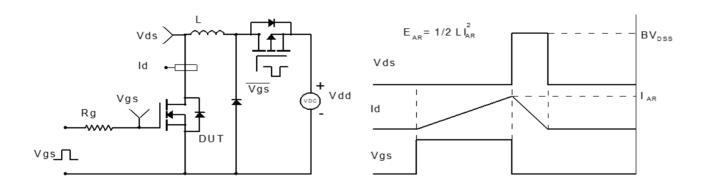


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

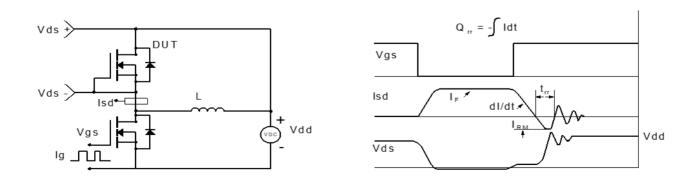
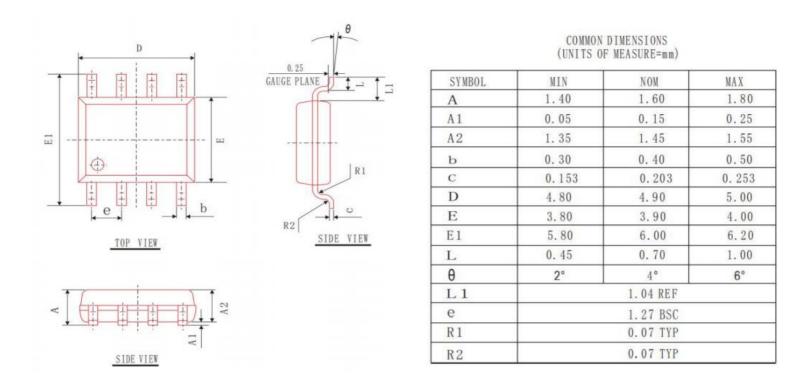


Figure 4: Diode Recovery Test Circuit & Waveform



Package Mechanical Data-SOP-8



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